

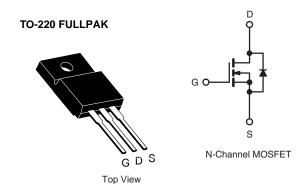
# N-Channel 550V (D-S) Power MOSFET

PRODUCT SUMMA	RY	
V <sub>DS</sub> (V)	550	)
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.26
Q <sub>g</sub> max. (nC)	150	1
Q <sub>gs</sub> (nC)	12	
Q <sub>gd</sub> (nC)	25	
Configuration	Sing	le

#### **FEATURES**

- Optimal Design
  - Low Area Specific On-Resistance
  - Low Input Capacitance (Ciss)
  - Reduced Capacitive Switching Losses
  - High Body Diode Ruggedness
  - Avalanche Energy Rated (UIS)
- Optimal Efficiency and Operation
  - Low Cost
  - Simple Gate Drive Circuitry
  - Low Figure-of-Merit (FOM):  $R_{on} \times Q_g$
  - Fast Switching





#### **APPLICATIONS**

- Consumer Electronics
  - Displays (LCD or Plasma TV)
- Server and Telecom Power Supplies
  - SMPS
- Industrial
  - Welding
  - Induction Heating
  - Motor Drives
- · Battery Chargers
- SMPS
  - Power Factor Correction (PFC)

ABSOLUTE MAXIMUM RATINGS ( $T_C$	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V <sub>DS</sub>	550	
Gate-Source Voltage			V	± 20	V
Gate-Source Voltage AC (f > 1 Hz)			$V_{GS}$	30	
Continuous Drain Current (T, = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C		18	
Continuous Drain Current (1) = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	11	Α
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	56	
Linear Derating Factor				2.2	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	281	mJ
Maximum Power Dissipation			$P_{D}$	60	W
Operating Junction and Storage Temperature Range	е		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C
Drain-Source Voltage Slope	$T_{J} = 1$	125 °C	dV/dt	24	V/ns
Reverse Diode dV/dt <sup>d</sup>			av/at	0.36	V/IIS
Soldering Recommendations (Peak Temperature)	for	10 s		300°	°C

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 10 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 7.5 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \leq I_D$ , starting  $T_J = 25~^{\circ}C$ .



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.45	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				L	L		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		550	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I <sub>D</sub> = 250 μA	-	0.56	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2	-	4	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		= 500 V, V <sub>GS</sub> = 0 V /, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	1 10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		-	0.26	-	Ω
Forward Transconductance	9 <sub>fs</sub>		= 50 V, I <sub>D</sub> = 10 A	-	12	-	S
Dynamic	0.0		, 5	L	l		
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ ,		-	3094	-	T T
Output Capacitance	C <sub>oss</sub>		$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$	-	152	-	-
Reverse Transfer Capacitance	C <sub>rss</sub>		f = 1 MHz		13	-	pF
Effective output capacitance, energy related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 0 V to 400 V		-	131	-	
Effective output capacitance, time related <sup>b</sup>	C <sub>o(tr)</sub>			-	189	-	
Total Gate Charge	$Q_g$			-	80	150	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V I <sub>D</sub> = 10 A, V <sub>DS</sub> = 400 V		-	12	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	25	-	
Turn-On Delay Time	t <sub>d(on)</sub>			-	24	50	
Rise Time	t <sub>r</sub>	$V_{DD} = 400 \text{ V}, I_{D} = 10 \text{ A}, V_{GS} = 10 \text{ V}, R_{g} = 9.1 \Omega$		-	31	62	no
Turn-Off Delay Time	t <sub>d(off)</sub>			-	117	176	ns
Fall Time	t <sub>f</sub>			-	56	112	
Gate Input Resistance	$R_{g}$	f = 1 MHz, open drain		-	1.8	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym showing the	MOSFET symbol showing the		-	20	_
Pulsed Diode Forward Current	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	80	A
Diode Forward Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C},  I_S = 10  \text{A},  V_{GS} = 0  \text{V}$		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>			-	437	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25 \text{ °C, I}_F = I_S = 10 \text{ A,}$ $dI/dt = 100 \text{ A/}\mu\text{s, V}_R = 20 \text{ V}$		-	5.9	-	μC
Reverse Recovery Current	I <sub>RRM</sub>				25	-	Α

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

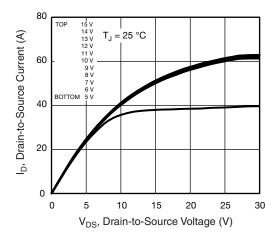


Fig. 1 - Typical Output Characteristics

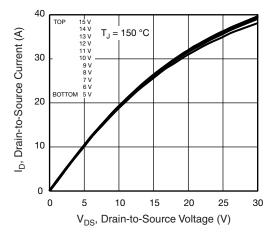


Fig. 2 - Typical Output Characteristics

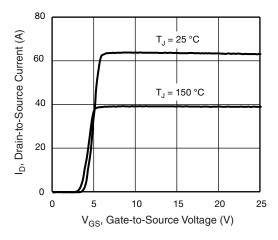


Fig. 3 - Typical Transfer Characteristics

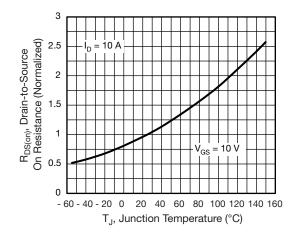


Fig. 4 - Normalized On-Resistance vs. Temperature

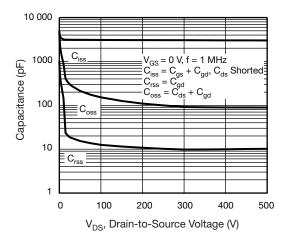


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

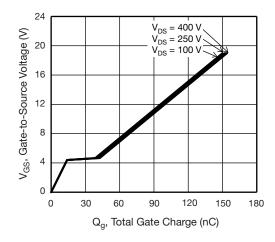


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



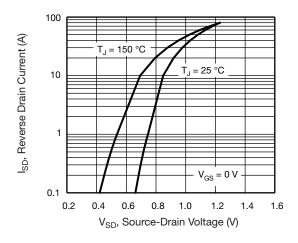


Fig. 7 - Typical Source-Drain Diode Forward Voltage

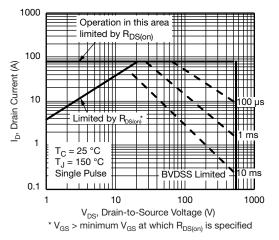


Fig. 8 - Maximum Safe Operating Area

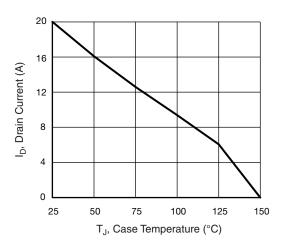


Fig. 9 - Maximum Drain Current vs. Case Temperature

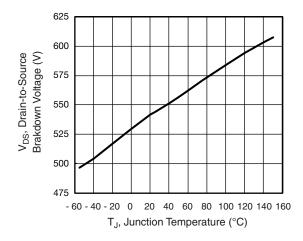


Fig. 10 - Temperature vs. Drain-to-Source Voltage

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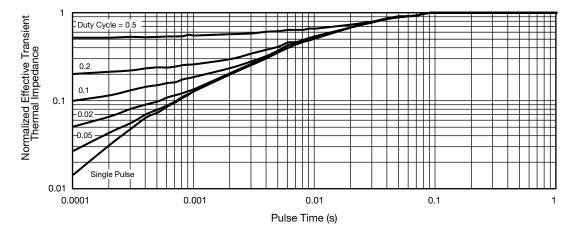


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



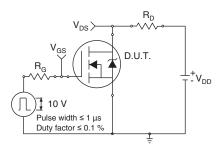


Fig. 12 - Switching Time Test Circuit

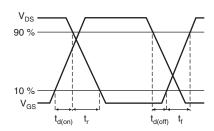


Fig. 13 - Switching Time Waveforms

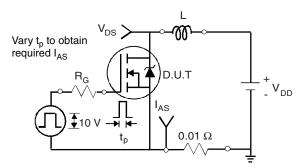


Fig. 14 - Unclamped Inductive Test Circuit

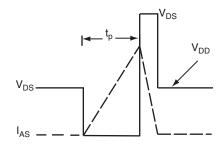


Fig. 15 - Unclamped Inductive Waveforms

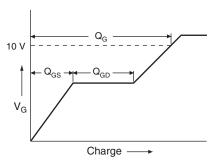


Fig. 16 - Basic Gate Charge Waveform

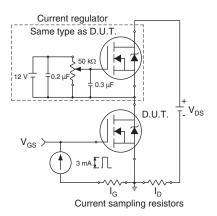
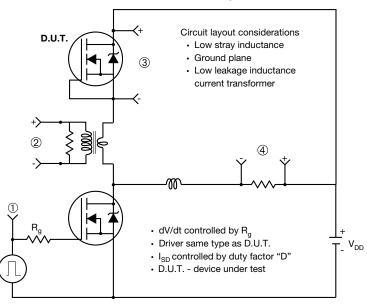


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



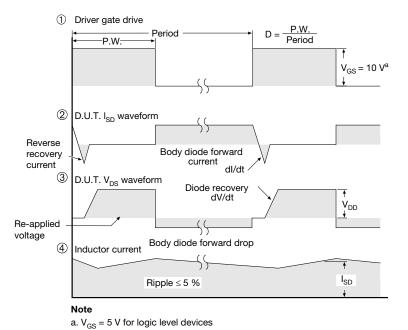
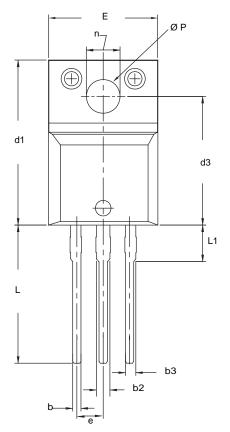


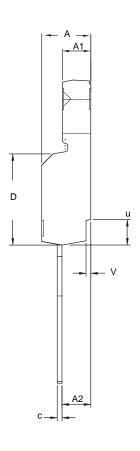
Fig. 18 - For N-Channel

服务热线:400-655-8788 6



### **TO-220 FULLPAK (HIGH VOLTAGE)**





	MILLIN	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
Е	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

DWG: 5972

- To be used only for process drawing.
  These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
  All critical dimensions should C meet C<sub>pk</sub> > 1.33.
  All dimensions include burrs and plating thickness.
  No chipping or package damage.

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